

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) with (detec or detecting or detected or detection) with (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:54
L2	1	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) with (detec or detecting or detected or detection or defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L3	22	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) and (detec or detecting or detected or detection or defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L4	1	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) same (detec or detecting or detected or detection or defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L5	22	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) and (detec or detecting or detected or detection or defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L6	11	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) and (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L7	1	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))).clm. and (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:55
L8	0	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))).clm. and (defect or defective).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:56
L9	1	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))).clm. and (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:56



L10	3	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))).ti,ab,clm. and (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:57
L11	4	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))).ti,ab,clm. and (detect or detecting or detected or detected or defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:57
L12	0	10/711083	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:57
L13	49	((cnt near fet) or ((carbon near nanotube near field near effect near transistor)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:58
L14	0	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) and (defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:58
L15	11	((cnt near fet) or ((carbon near nanotube near field near effect near transistor))) and (defect or defective)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:58
L16	8015	(detect or detecting or detected or detection) near10 (defect or defective) near10 (circuit or circuitry)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 19:59
L17	8	(fet or (field adj effect adj transistor)) near10 (detect or detecting or detected or detection) near10 (defect or defective) near10 (circuit or circuitry)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 20:01
L18	4	(fet or (field adj effect adj transistor)) near5 (detect or detecting or detected or detection) near5 (defect or defective) near5 (circuit or circuitry)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/08 20:01